



# 12th IEEE European Test Symposium

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<http://www.ieee-ets.org>



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## Call for Papers

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics, and new trends in the area of electronic-based circuit and system testing. In 2007, ETS will take place in Freiburg, Southern Germany's Black Forest area. ETS'07 is being organized by the Albert-Ludwigs-University of Freiburg, which celebrates its 550-year anniversary in 2007, and is sponsored by the Test Technology Technical Council (TTTC) of the IEEE Computer Society.

You are invited to participate and submit your contributions to ETS'07. The areas of interest of ETS'07 include (but are not limited to) the following topics:

- Automatic Test Generation
- Fault Modeling and Simulation
- Current-Based Test
- Power Issues in Test
- Thermal Test
- Delay and Performance Test
- High-Speed IO/Interconnect Test
- Signal Integrity Test
- Nanometer Technologies Test
- ATE Hardware and Software
- Standards in Testing
- Test(ability) Synthesis
- Built-In Self Test (BIST)
- Design for Test(ability) (DfT)
- Test Data Compression
- On-Line Test
- Self-Repair Methodologies
- Test of Reconfigurable Systems
- Analog, Mixed-Signal, RF Test
- Memory Test and Repair
- Microprocessor Test
- MEMS and Nanotechnology Test
- Failure Analysis
- Diagnosis and Debug
- Design Verification and Validation
- Test Quality and Reliability
- Yield Analysis and Enhancement
- Defect and Fault Tolerance
- Board and System Test
- (Embedded) System Test
- High-Level DfT and TPG
- System-in-Package (SiP) Test
- System-on-Chip (SoC) Test

**Publications** – ETS'07 will produce *Formal Proceedings* of selected papers, published by the IEEE Computer Society, and an *Informal Digest*. A post-conference CD-ROM with papers, presentation slides, and photos will be mailed to all participants. The best contributions will be selected for submission to regular issues of the "Journal of Electronic Testing: Theory and Applications" (JETTA), published by Kluwer Academic Publishers. ETS'07 will present a Best Paper Award at ETS'08.

**Submissions** – ETS'07 seeks original, unpublished contributions of the following types.

- Scientific papers for the Formal Proceedings.
- Workshop-type papers for the Informal Digest, including 'emerging ideas' and 'case studies'.
- Proposals for panels, embedded tutorials, and other special sessions.
- 'Vendor Session' presentations, for which corresponding white papers can be included in the Informal Digest.

Detailed submission instructions, including selection criteria and publication policies, for the various types of contributions are posted on the ETS'07 web page.

TTTC Test Technology Educational Program (TTEP) tutorials on emerging test technology topics will be offered during ETS 2007. Tutorial proposals should be submitted according to TTEP 2007 submission deadlines (<http://computer.org/tab/ttcc/teg/ttep>).

**Key Dates:**

- Submission deadline : **December 8, 2006**
- Notification of acceptance : **February 14, 2007**
- Camera-ready manuscript : **March 11, 2007**

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